

|                                   |                                       |  |   |             |
|-----------------------------------|---------------------------------------|--|---|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/758,868 |  | Applicant(s)/Patent Under<br>Reexamination<br>KANG, TAE-JIN |             |
|                                   | Examiner<br>Tsung-Yin Tsai            |  | Art Unit<br>2609  | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name                | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-5,936,665 A                                   | 08-1999         | Vachtsevanos et al. | 348/91         |
| * | B | US-2002/0081015 A1                               | 06-2002         | Alkemper et al.     | 382/141        |
|   | C | US-  |                 |                     |                |
|   | D | US-  |                 |                     |                |
|   | E | US-  |                 |                     |                |
|   | F | US-  |                 |                     |                |
|   | G | US-  |                 |                     |                |
|   | H | US-  |                 |                     |                |
|   | I | US-  |                 |                     |                |
|   | J | US-  |                 |                     |                |
|   | K | US-  |                 |                     |                |
|   | L | US-  |                 |                     |                |
|   | M | US-  |                 |                     |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)  |
|---|---|--|
|   | U | Soo Chang Kim and Tae Jin Kang:"Automatic Evaluation of Fabric Pilling Using a 3-D Non-contact Scanning System" ; Instrumentation and Measurement Technology Conference, 2005. IMTC 2005. Proceedings of the IEEE Volume 1, 16-19 May 2005 Page(s):628 - 632) disclose automatic evaluation of fabric pilling using a 3-D Non-contact Scanning Syste |
|   | V | Fazekas, Z.; Komuves, J.; Renyi, I.; Surjan, L.:"Automatic visual assessment of fabric quality";Industrial Electronics, 1999. ISIE '99. Proceedings of the IEEE International Symposium on. Volume 1, 12-16 July 1999 Page(s): 178 - 182 vol.1 Digital Object Identifier 10.1109/ISIE.1999.801780. Disclose automatic visual assessment of fabric    |
|   | W |  |
|   | X |  |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.